

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3	"6633391"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 14:17
L2	53	"6334960"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 15:56
L3	1	"02092603"	JPO	OR	ON	2005/07/19 15:57
L4	1	"02024848"	JPO	OR	ON	2005/07/19 15:58
L5	30	KURIKAWA near AKINORI	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 16:03
L6	2035	stamper near2 mold\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 16:04
L7	3	template near6 (stamper near2 mold\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 16:05
L8	27	((measur\$3 or detect\$3) or sens\$3) near15 (film near6 substrate)) and (stamper near2 mold\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:42
L9	353	(detector or sensor) and (stamper near2 mold\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:42
L10	1	(detector or sensor) near9 (film near4 substrate) and (stamper near2 mold\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:43

L11	6	(detector or sensor) near9 (pattern near4 substrate) and (stamper near2 mold\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:44
L12	15	9 and substrate near2 defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:46
L13	94	9 and defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:46
L14	44	13 and align\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:46
L15	1	13 and align\$4 near3 error	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:48
L16	1	13 and align\$4 and critical near dimension	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:49
L17	44	13 and align\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:55
L18	2	13 and critical near dimension	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:49

L19	7021	((measur\$3 or detect\$3) near6 (film near4 substrate))".clm"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:56
L20	0	(imprint near head near defect).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:56
L21	714	((measur\$3 or detect\$3) near6 (film near4 substrate)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:56
L22	22	(imprint near head).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:58
L23	36	21 and plurality near2 (regions or area)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/19 17:58